

Notice of References Cited	Application/Control No. 10/572,589		Applicant(s)/Patent Under Reexamination YAMAUCHI ET AL.	
	Examiner SHIN-HON CHEN		Art Unit 2431	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,093,296	08-2006	Nusser et al.	726/26
*	C	US-2002/0120577	08-2002	Hans et al.	705/59
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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